



Features

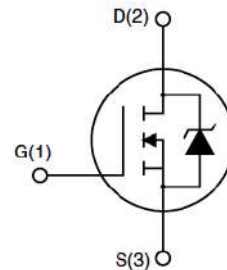
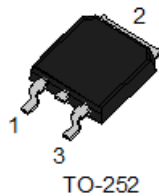
- 30V,75A
- $R_{DS(ON)}=4.8m\Omega$ (Typ.) @ $V_{GS}=10V$
- $R_{DS(ON)}=6.5m\Omega$ (Typ.) @ $V_{GS}=4.5V$
- Advanced Trench Technology
- Provide Excellent $R_{DS(ON)}$ and Low Gate Charge

Application

- Load Switch
- PWM Application

Product Summary

| | | |
|-------------------------------|-----|------------|
| V_{DS} | 30 | V |
| $R_{DS(on),TYP}@ V_{GS}=10 V$ | 4.8 | m Ω |
| I_D | 75 | A |



Absolute Maximum Ratings (T_C=25°C unless otherwise specified)

| Symbol | Parameter | | Max. | Units |
|-----------------------------------|---|------------------------|-------------|-------|
| V_{DSS} | Drain-Source Voltage | | 30 | V |
| V_{GSS} | Gate-Source Voltage | | ± 20 | V |
| I_D | Continuous Drain Current | T _C = 25°C | 75 | A |
| | | T _C = 100°C | 50 | A |
| I_{DM} | Pulsed Drain Current ^{note1} | | 300 | A |
| E_{AS} | Single Pulsed Avalanche Energy ^{note2} | | 88 | mJ |
| P_D | Power Dissipation | T _C = 25°C | 75 | W |
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case | | 2 | °C/W |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient | | 65 | |
| T _J , T _{STG} | Operating and Storage Temperature Range | | -55 to +175 | °C |

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise specified)

| Symbol | Parameter | Test Condition | Min. | Typ. | Max. | Units |
|---|---|--|------|------|-----------|------------|
| Off Characteristic | | | | | | |
| $V_{(BR)DSS}$ | Drain-Source Breakdown Voltage | $V_{GS}=0V, I_D=250\mu A$ | 30 | - | - | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS}=30V, V_{GS}=0V, T_J=25^\circ\text{C}$ | - | - | 1 | μA |
| | | $V_{DS}=24V, V_{GS}=0V, T_J=125^\circ\text{C}$ | - | - | 10 | |
| I_{GSS} | Gate to Body Leakage Current | $V_{DS}=0V, V_{GS}=\pm 20V$ | - | - | ± 100 | nA |
| On Characteristics | | | | | | |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=250\mu A$ | 1.0 | 1.6 | 2.5 | V |
| $R_{DS(on)}$ | Static Drain-Source on-Resistance <small>note3</small> | $V_{GS}=10V, I_D=20A$ | - | 4.8 | 6 | m Ω |
| | | $V_{GS}=4.5V, I_D=10A$ | - | 6.5 | 12 | |
| g_{FS} | Forward Transconductance | $V_{DS}=5V, I_D=10A$ | - | 20 | - | S |
| Dynamic Characteristics | | | | | | |
| C_{iss} | Input Capacitance | $V_{DS}=25V, V_{GS}=0V, f=1.0\text{MHz}$ | - | 1560 | - | pF |
| C_{oss} | Output Capacitance | | - | 220 | - | pF |
| C_{rss} | Reverse Transfer Capacitance | | - | 178 | - | pF |
| Q_g | Total Gate Charge | $V_{DS}=15V, I_D=20A, V_{GS}=4.5V$ | - | 11.1 | - | nC |
| Q_{gs} | Gate-Source Charge | | - | 1.85 | - | nC |
| Q_{gd} | Gate-Drain("Miller") Charge | | - | 6.8 | - | nC |
| Switching Characteristics | | | | | | |
| $t_{d(on)}$ | Turn-on Delay Time | $V_{DS}=15V, I_D=15A, R_G=3.3\Omega, V_{GS}=10V$ | - | 7.5 | - | ns |
| t_r | Turn-on Rise Time | | - | 14.5 | - | ns |
| $t_{d(off)}$ | Turn-off Delay Time | | - | 35.2 | - | ns |
| t_f | Turn-off Fall Time | | - | 9.6 | - | ns |
| Drain-Source Diode Characteristics and Maximum Ratings | | | | | | |
| I_S | Maximum Continuous Drain to Source Diode Forward Current | | - | - | 75 | A |
| I_{SM} | Maximum Pulsed Drain to Source Diode Forward Current | | - | - | 300 | A |
| V_{SD} | Drain to Source Diode Forward Voltage | $V_{GS}=0V, I_S=30A$ | - | - | 1.2 | V |
| t_{rr} | Body Diode Reverse Recovery Time | $I_S=30A, dI/dt=100A/\mu s$ | - | 32 | - | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | | - | 12 | - | nC |

- Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
 2. EAS condition: $T_J=25^\circ\text{C}, V_{DD}=25V, V_{GS}=10V, L=0.1\text{mH}, I_{AS}=42A, R_G=25\Omega$
 3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$

Typical Performance Characteristics

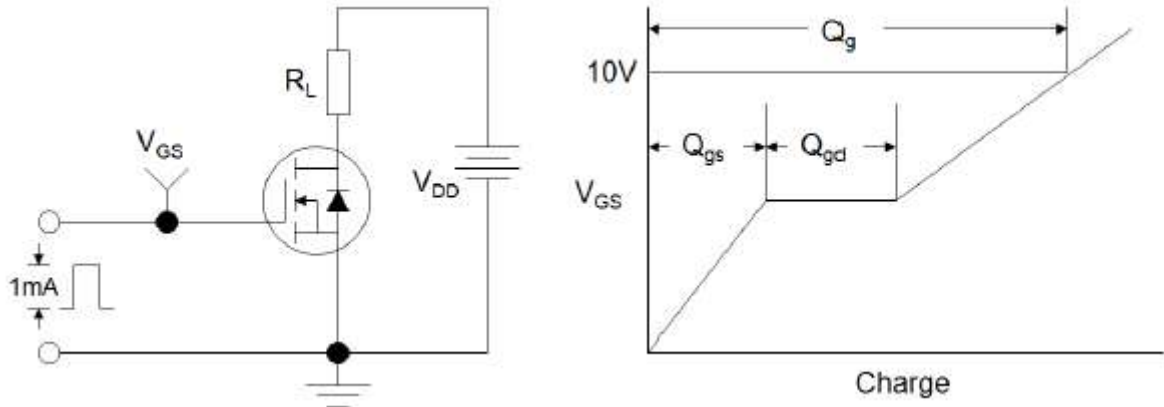


Figure1:Gate Charge Test Circuit & Waveform

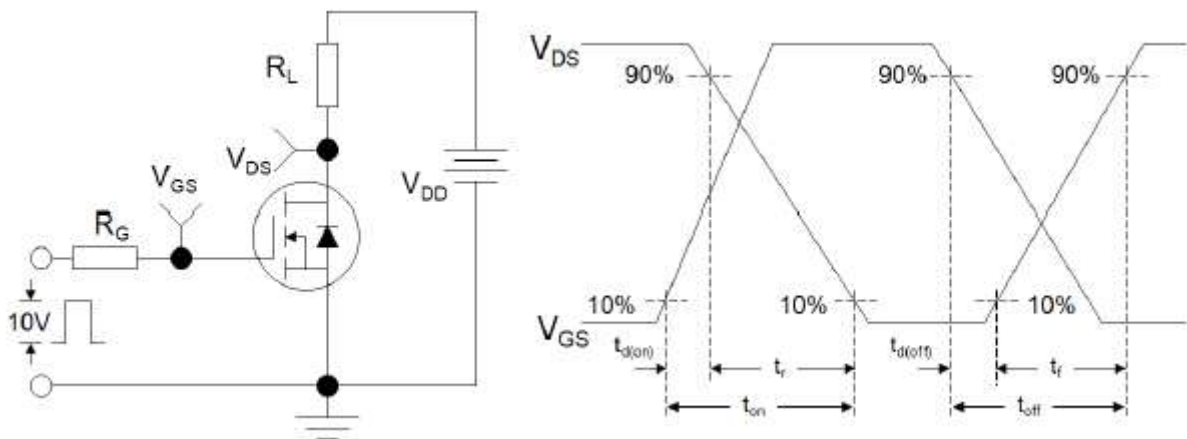


Figure 2: Resistive Switching Test Circuit & Waveforms

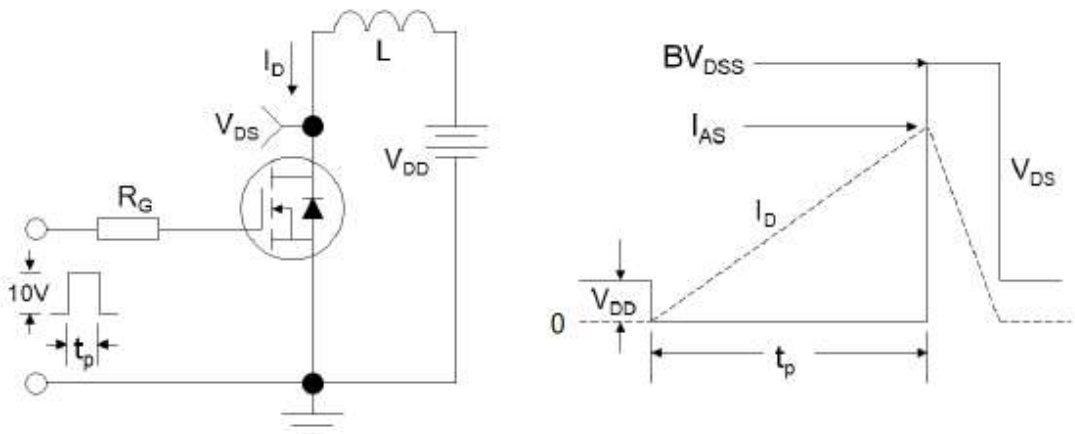


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

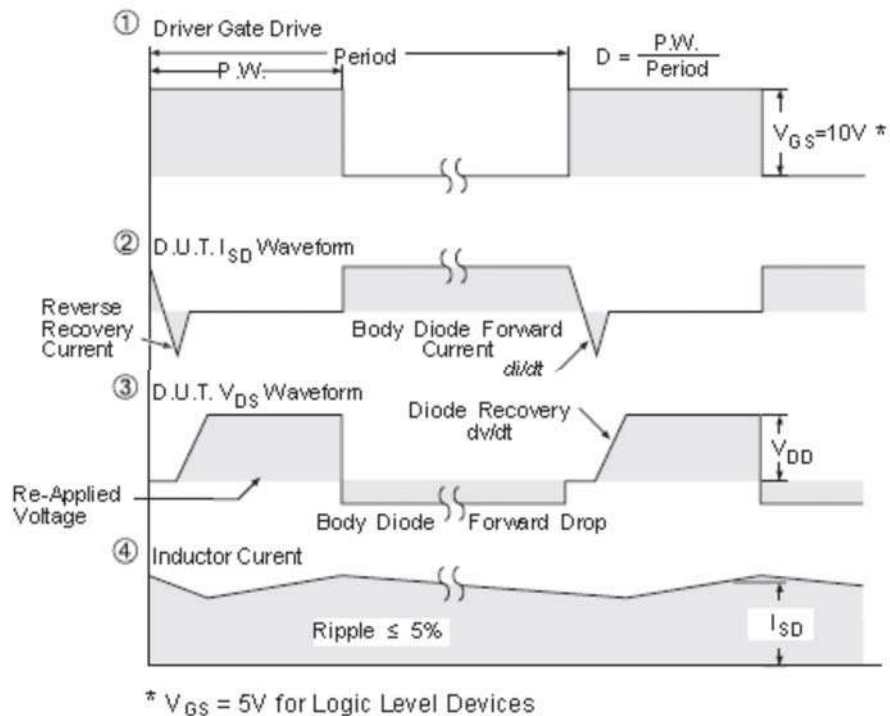
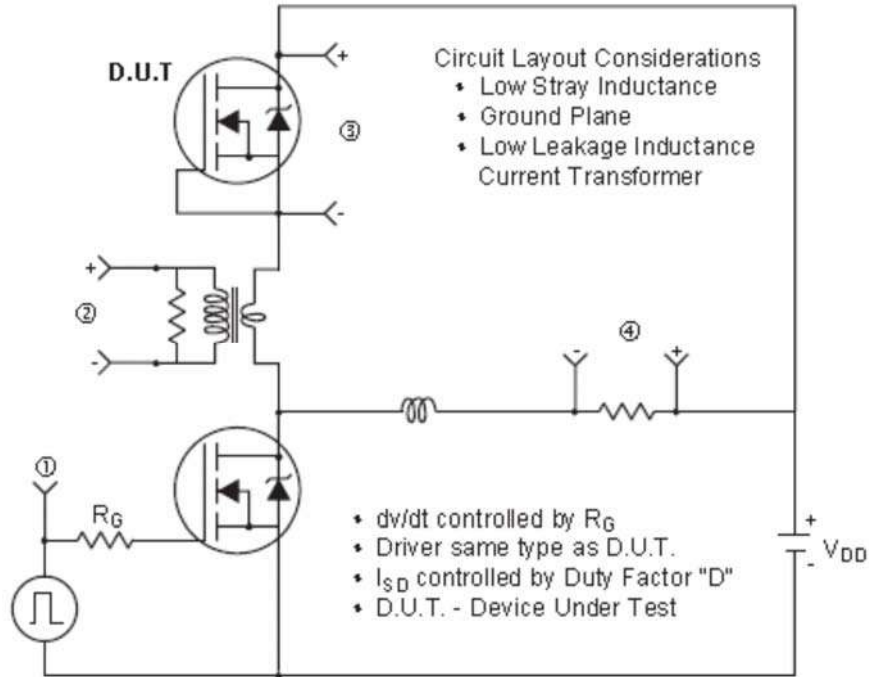
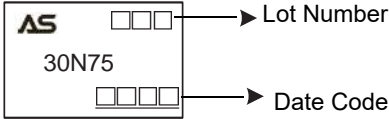


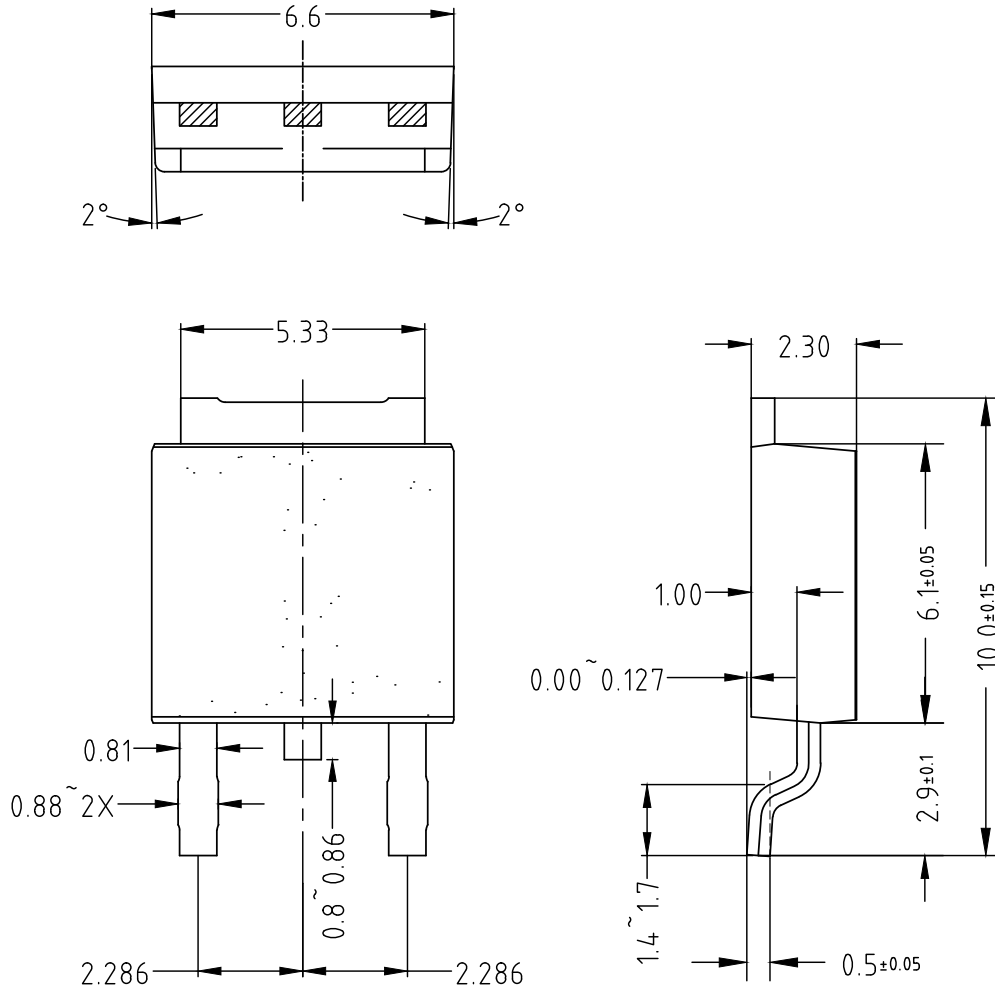
Figure 4: Peak Diode Recovery dv/dt Test Circuit & Waveforms (For N-channel)

Ordering and Marking Information

| Ordering Device No. | Marking | Package | Packing | Quantity |
|---------------------|---------|---------|------------|-----------|
| ASDM30N75KQ-R | 30N75 | TO-252 | Tape/ Reel | 2500/Reel |

| PACKAGE | MARKING |
|---------|---|
| TO-252 |  <p>AS □□□ → Lot Number 30N75 □□□□ → Date Code</p> |

TO-252



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